

FDD8445

N-Channel PowerTrench® MOSFET 40V, 50A, 8.7m Ω

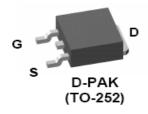
Features

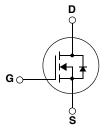
- $R_{DS(ON)} = 6.7 \text{ m}\Omega$ (Typ), $V_{GS} = 10V$, $I_D=50A$
- $Q_{g(10)} = 45nC \text{ (Typ)}, V_{GS}=10V$
- Low Miller Charge
- Low Qrr Body Diode
- UIS Capability (Single Pulse/ Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant



Applications

- Automotive Engine Control
- Powertrain Management
- Solenoid and Motor Drivers
- Electronic Transmission
- Distributed Power Architecture and VRMs
- Primary Switch for 12V Systems





Absolute Maximum Ratings $T_c = 25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DSS}	Drain to Source Voltage	40	V
V_{GS}	Gate to Source Voltage	±20	V
	Drain Current Continuous (V _{GS} =10v) (Note 1)	70	Α
I_D Continuous ($V_{GS}=10v$, with $R_{\theta,JA}=52^{\circ}C/W$)		15.2	Α
	Pulsed	Figure 4	
E _{AS}	Single Pulse Avalanche Energy (Note2)	144	mJ
D	Power Dissipation	79	W
P_{D}	Derate above 25°C	0.53	W/°C
T _J , T _{STG}	Operating and Storage Temperature	-55 to +175	°C

Thermal Characteristics

R_{θ}	JC	Thermal Resistance, Junction to Case	1.9	°C/W
R_{θ}	JA	Thermal Resistance, Junction to Ambient TO-252, lin ² copper pad area	52	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8445	FDD8445	TO-252AA	13"	12mm	2500 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Co	nditions	Min	Тур	Max	Units
Off Chara	acteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_0$	_{GS} = 0V	40	-	-	٧
ı	Zero Gate Voltage Drain Current	$V_{DS} = 32V$		-	-	1	μΑ
IDSS	Zero Gate Voltage Drain Current	$V_{GS} = 0V$	T _J =150°C	-	-	250	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	2.8	4	V
		$I_D = 50A, V_{GS} = 10V$	-	6.7	8.7	
R _{DS(ON)}	Drain to Source On Resistance	$I_D = 50A$, $V_{GS} = 10V$, $T_J = 175^{\circ}C$	-	12.5	16.3	mΩ

Dynamic Characteristics

C _{ISS}	Input Capacitance	.,		-	3040	4050	pF
Coss	Output Capacitance	── V _{DS} = 25V, V _{GS} ── f = 1MHz	$V_{DS} = 25V, V_{GS} = 0V,$		295	390	pF
C _{RSS}	Reverse Transfer Capacitance	1 - 1101112		-	178	270	pF
R _G	Gate Resistance	f = 1MHz		-	1.7	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	V _{GS} = 0 to 10V		-	45	59	nC
Q _{g(5)}	Total Gate Charge at 5V	$V_{GS} = 0$ to 5V		-	17	22	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0$ to $2V$	V _{DD} =20V,	-	5.8	7.6	nC
Q_{gs}	Gate to Source Gate Charge		$I_D = 50A$	-	12.5	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau			-	9.5	-	nC
Q _{qd}	Gate to Drain "Miller" Charge			-	10.5	-	nC

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Switching	g Characteristics					
t _(on)	Turn-On Time		-	-	138	ns
t _{d(on)}	Turn-On Delay Time		-	10	-	ns
t _r	Turn-On Rise Time	$V_{DD} = 20V, I_{D} = 50A$	-	82	-	ns
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = 20V, I_{D} = 50A$ $V_{GS} = 10V, R_{GS} = 2\Omega$	-	26	-	ns
t _f	Turn-Off Fall Time		-	9.6	-	ns
t _{off}	Turn-Off Time		-	-	53	ns

Drain-Source Diode Characteristics

V	Source to Drain Diode Voltage	I _{SD} =50A	1.25 1.0	V		
V _{SD}	Source to Drain Diode Voltage	I _{SD} =25A	-	-	1.0	٧
t _{rr}	Reverse Recovery Time	I_F = 50A, dI_F/dt =100A/ μ s	-	-	39	ns
Q _{rr}	Reverse Recovery Charge	I _F = 50A, dI _F /dt=100A/μs	-	-	38	nC

Notes:1: Maximum package current capability is 50A.
2: Starting $T_J = 25^{\circ}C$, L=0.18mH, I_{AS} =40A.

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/
All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

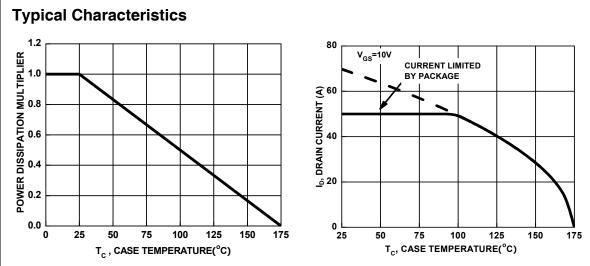


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

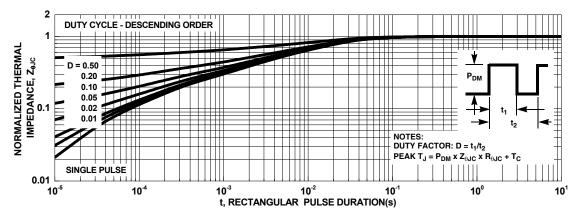


Figure 3. Normalized Maximum Transient Thermal Impedance

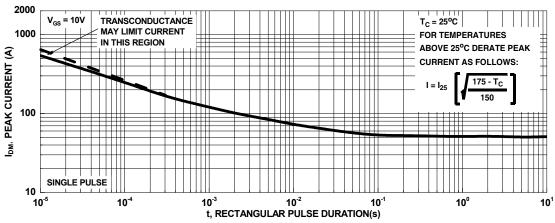
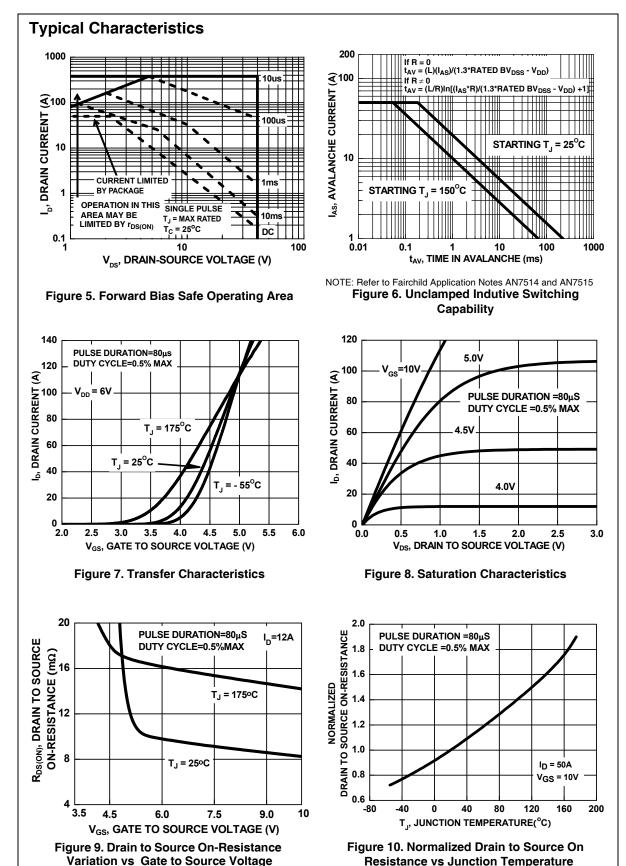


Figure 4. Peak Current Capability



Typical Characteristics

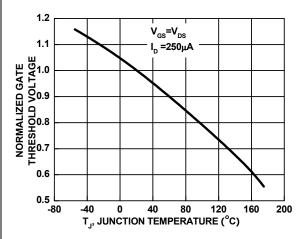


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

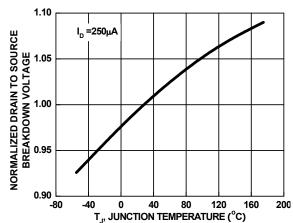


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

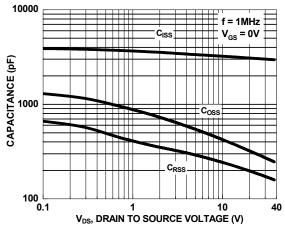


Figure 13. Capacitance vs Drain to Source Voltage

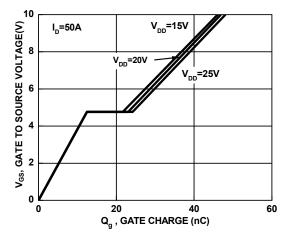


Figure 14. Gate Charge vs Gate to Source Voltage





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